

# Search Notes



Application/Control No.

10/686,636

Examiner

Judson H. Jones

Applicant(s)/Patent under  
Reexamination

TANAKA, YONETA

Art Unit

2834

## SEARCHED

Class	Subclass	Date	Examiner
310	12	6/2/2005	JHJ
355	53,72	6/2/2005	JHJ
118	728,729	6/2/2005	JHJ
33	568,573	6/2/2005	JHJ
above	searched	8/18/05	JHJ

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
above	searched	8/18/05	JHJ

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
USPTO BRS search search terms: wafer and stage same (piezo or piezoelect\$8) USPAT, PGPUB, EPO, JPO and Derwent	6/4/2005	JHJ